

## USB 3.0 Product Test Matrix

		USB 3.0 xHCI /SuperSpeed Testing								USB 2.0 LS/FS/HS Testing				
		USBCV Chap 9 Tests	USBCV Class Tests	xHCI Host Tests	3.0 Electrical	3.0 Interop with U1/U2 enabled	3.0 Backwards Compatibility with U1/U2	Link Testing	SS Hub CV	Current Test Measurement	USBCV Chap 9	USBCV Class Tests	2.0 Gold Tree Interop using EHCI	2.0 Electrical
xHCI Host	Silicon and IP	All SS Silicon	All tests, all SS silicon	Full Test Suite	✓	✓	✓	✓	n/a	n/a	All speeds	All	n/a	✓
	End Product	All SS Silicon	All tests, all SS silicon	Subset	✓	✓	✓	✓	n/a	n/a	All speeds	All	n/a	✓
USB 3.0 Devices: Silicon, IP, End Product	Device	✓	MSC UASP HID UVC PHDC OTG	n/a	✓	✓	n/a	✓	n/a	✓	Run for all 2.0 supported speeds	MSC UASP HID UVC PHDC OTG	✓	✓
	Hub	✓	Hub tests + all devices DS	SS loop-backs behind SS hub	Up-stream and down-stream ports	✓	Hub Si Only	✓	✓	✓	All speeds, all device classes DS	Hub tests + all devices DS	✓	Up-stream and down-stream ports

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Test Notes:	Host Si: xHCI Loopback Tests and xHCI Interface Tests. Host End Products: xHCI Interface Tests for End Products only.
	3.0 Electricals on Agilent or LeCroy or Tek using external BERT
	Backwards Compatibility includes testing 150 popular 2.0 devices for Host silicon and IP. End product will test a subset of 150
	Chapter 9 CV tests must be run at the root port for SS and also behind a SS hub.
	3.0 Hubs must have Hub TT tests run on the HS portion of the hub if the hub is not a separate, certified 2.0 hub chip.
	Current measurement with CV : unconfigured, U1, U2, U3. Current measurement with host driver stack: Operating current.
	Peripherals must pass all applicable class tests in USB30CV and USB20CV